

## Power Supply Test Systems

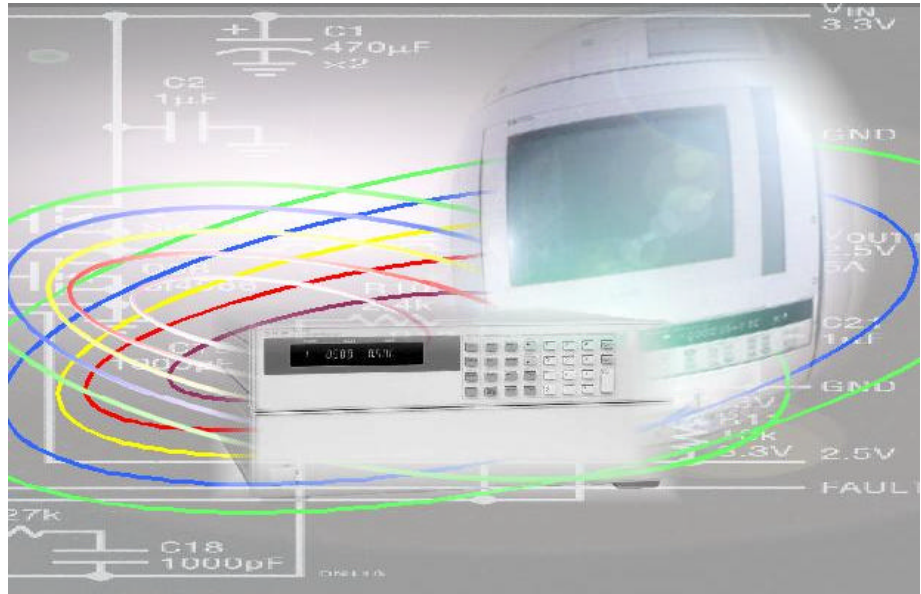
- Test routines for up to 6 outputs
- Parallel test for higher throughput
- 0V load operation
- Data logging to popular spreadsheet formats
- Interface to automation and HASS systems
- Network support

### General Description

The EP-300x Power Supply Test System is based on off-the-shelf instruments from Agilent Technologies, installed in a 6-foot 19" rack. The system incorporates the latest N3300 series electronic loads from Agilent, which operate with full stability at zero volts. The ES-1000 Test Management Software provided with the test system allows up to six UUTs (units-under-test) to be tested in parallel for throughput improvements of three-to-five times over a single-well tester<sup>1</sup>. By using standard bench equipment as the base for the test system, cost of calibration and maintenance is lowered. Agilent's proven reliability and our test system's user-friendly diagnostic feature help to minimize system downtime.

The EP-3000 system is designed for the modern high-volume manufacturing environment. Its software can be run from a standalone controller or via the network, and test data is logged in a standard spreadsheet-readable format.

For even higher throughput, our system has interface options



to automated conveyor and HASS (Highly Accelerated Stress Screening) systems.

### Test Library

The test library, written in the Agilent VEE Pro Graphical Programming Language, provides most standard DC/DC power supply test functions. Standard tests include voltage regulation, output PARD, input ripple current, switching frequency, short circuit current, low input shutdown, dynamic load, and many more. The ease-of-use of graphical programming means you will be customizing your

own tests to the library in a matter of weeks.

### Specifications

Input supply:

**DC/DC:** 0-80V, 0-30A

**AC/DC:** Voltage- 300Vrms

Power- 750VA, 1750VA, 3000VA or 4500VA

One to six load outputs:

Voltage: 0-60V

Current: 0-30A, 0-60A or 0-120A

Basic measurement accuracy:

0.002% + 0.6mV, 0.002% + 0.6mA

<sup>1</sup> Actual throughput increase depends on combination of tests.